

Nove pobude za delo v IEC – MAJ 2024

Referenčna oznaka	Naslov	Tehnični odbor
110/1650/NP	PNW 110-1650 ED1: Eyewear display - Part 50: User interaction	TC 110
113/827/NP	PNW 113-827 ED1: 62607-8-5: Nanomanufacturing - Key Control Characteristics - Part 8-5: Nano-enabled metal-oxide interfacial devices - Oxygen distribution: Secondary ion mass spectrometry (SIMS)	TC 113
113/828/NP	PNW TS 113-828 ED1: Nanomanufacturing - Key control characteristics - Part 8-6: Metal-oxide interfacial devices - Optical properties: Spectroscopic ellipsometry	TC 113
113/831/NP	PNW TS 113-831 ED1: IEC TS 62607-3-5 Nanomanufacturing - Key control characteristics - Part 3-5: Nanophotonic products - Light conversion efficiency of quantum dot-based light conversion films: luminance meter	TC 113
113/832/NP	PNW TS 113-832 ED1: IEC TS 62607-3-4 Nanomanufacturing - Key control characteristics - Part 3-4: Nanophotonic products - Luminance of quantum-dot-based light emitting diodes: integrating sphere, spectroradiometer	TC 113
113/833/NP	PNW TS 113-833 ED1: <p>Nanomanufacturing - Product specification - Part 5-5: Nanoenabled energy storage - Detail specification: Graphene - carbon nanotube suspension for conductive agent in</p> <p>Li-ion batteries</p>	TC 113
114/526/NP	PNW TS 114-526 ED1: Measurement and characterization of turbulence	TC 114
116/768/NP	PNW 116-768 ED1: Electric motor-operated hand-held tools, transportable tools and lawn and garden machinery - Safety - Part 2-25: Particular requirements for hand-held chain beam saws	TC 116
119/491/NP	PNW 119-491 ED1: IEC 62899-202-14 ED1 Printed electronics - Part 202-14: Materials - Test methods of conductive ink suitability for screen printing	TC 119
119/492/NP	PNW 119-492 ED1: IEC 62899-202-13 ED1 Printed electronics - Part 202-13: Materials - Resistance measurement method for conductive layer in printed and in-mould electronics	TC 119
47/2847/NP	PNW 47-2847 ED1: Semiconductor devices - Performance evaluation of semiconductor processing components and inspection equipment - Part 3: Nano-scale wafer surface inspection method using UV light	TC 47
47/2848/NP	PNW 47-2848 ED1: Semiconductor devices - Performance evaluation of semiconductor processing components and inspection equipment - Part 4: Evaluation methods for dimensional accuracy of laser dicing process	TC 47
65A/1117/NP	PNW TS 65A-1117 ED1: Information technology ? Artificial intelligence ? Guidance and requirements for uncertainty quantification in AI systems	SC 65A
69/962/NP	PNW 69-962 ED1: Protocol for management of electric vehicles charging and discharging infrastructures ? Part 2: Technical protocol specifications and requirements	TC 69

72/1448/NP	PNW 72-1448 ED1: Automatic electrical controls ?Part 2-24: Particular requirements for displacement electrical controls	TC 72
80/1120/NP	PNW 80-1120 ED1: Maritime navigation and radiocommunication equipment and systems - Global navigation satellite systems (GNSS) - Part 8: Quasi-Zenith Satellite System (QZSS) receiver equipment - Performance requirements, methods of testing and required test results	TC 80
85/924/NP	PNW 85-924 ED1: Electrical safety in low voltage distribution systems up to 1.000 V AC and 1.500 V DC - Equipment for testing, monitoring or measuring the protective measures in energy distribution system - part 19: Monitoring device for earthing impedance in IT-systems	TC 85
86C/1928/NP	PNW 86C-1928 ED1: Fibre optic sensors ? Part 8-1: Pressure measurement ? Pressure sensors based on fibre Bragg gratings	SC 86C
8A/159/NP	PNW TS 8A-159 ED1: Grid compliance test for photovoltaic power plants	SC 8A
JTC1-SC25/3242/NP	PNW JTC1-SC25-3242 ED1: Information technology - Home Electronic System (HES) architecture - Part 5-105: Intelligent grouping and resource sharing for HES Class 2 and Class 3 - RA server-based smart lock application - Test and verification	ISO/IEC JTC 1/SC 25
JTC1-SC25/3243/NP	PNW JTC1-SC25-3243 ED1: Information technology ? Home Electronic System (HES) architecture - Part-4-303 Application protocol for electric vehicle supply equipment (EVSE) chargers and controllers	ISO/IEC JTC 1/SC 25
JTC1-SC25/3244/NP	PNW JTC1-SC25-3244 ED1: Information technology ? Home Electronic System (HES) architecture - Part-4-304 Application protocol for electric vehicle supply equipment (EVSE) charger and dischargers and controllers	ISO/IEC JTC 1/SC 25